

# RELIABILITY REPORT



### RELIABILITY DATA

LT3439/3465/3467/3469/3486/3506/ LT3804/25/37 LT4430

6/6/2008

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF FAILURES <sup>(2)</sup>
SOIC/SOT/MSOP	384	0318	0502	384.00	0
SSOP/TSSOP	395	0213	0727	413.50	0
	779			797.50	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	4,012	0326	0721	459.02	0
SSOP/TSSOP	757	0321	0717	88.18	0
QFN/DFN	697	0613	0707	64.70	0
	5,466			611.90	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	3,699	0232	0721	1,585.93	0
SSOP/TSSOP	631	0321	0717	147.90	0
QFN/DFN	577	0613	0707	125.65	0
	4,907			1,859.48	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,728	0326	0721	1,097.18	0
SSOP/TSSOP	612	0321	0717	88.50	0
QFN/DFN	429	0613	0707	59.00	0
	3,769			1,244.68	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 2.31 FITS

(3) Mean Time Between Failures in Years = 49,384

Note: 1 FIT = 1 Failure in One Billion Hours.